

| Form PTO-1449 (REV. 1/06) | | US Dept. of Commerce PATENT & TRADEMARK OFFICE | | ATTY DOCKET NO. 126821 | | APPLICATION NO. 10/565,968 | |
|---------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|-------------|-----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|---------|--------------------------------------|-----------------------------|--------------------------------|--|
| INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary) | | | | APPLICANT(S) Satoshi TAKEI et al. | | | |
| | | | | FILING DATE January 31, 2006 | | GROUP | |
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| EXAMINER P. Ashton | | | | DATE CONSIDERED 3-28-07 | | | |
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Date: May 15, 2006

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